

DEPFET Test Beam Analysis Workshop

Friday, 16 April 2010

TB Analysis: Basic Results - Seminar room on yellow floor (09:00 - 11:00)

time	[id] title	presenter
09:00	[3] Edge Effect and Gain Correction	KVASNICKA, Peter
09:20	[4] Extraction of DEPFET Sensor Resolution	KVASNICKA, Peter
09:40	[5] Status of Goettingen TB Analysis	Mr GEISLER, Christian
09:50	[6] TB Software	FOURLETOVA, Julia
10:10	[7] Discussion	Dr VOS, Marcel